

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
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Examiner

Binh X Tran

Art Unit

1765

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,177,023	01-2001	Shang et al.	118/728
	B	US-6,096,572	08-2000	Nakamura, Kenichi	438/158
	C	US-5,985,104	11-1999	Westwood, John David	204/192.12
	D	US-5,874,361	02-1999	Collins et al.	216/67
	E	US-5,665,167	09-1997	Deguchi et al.	118/723E
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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